

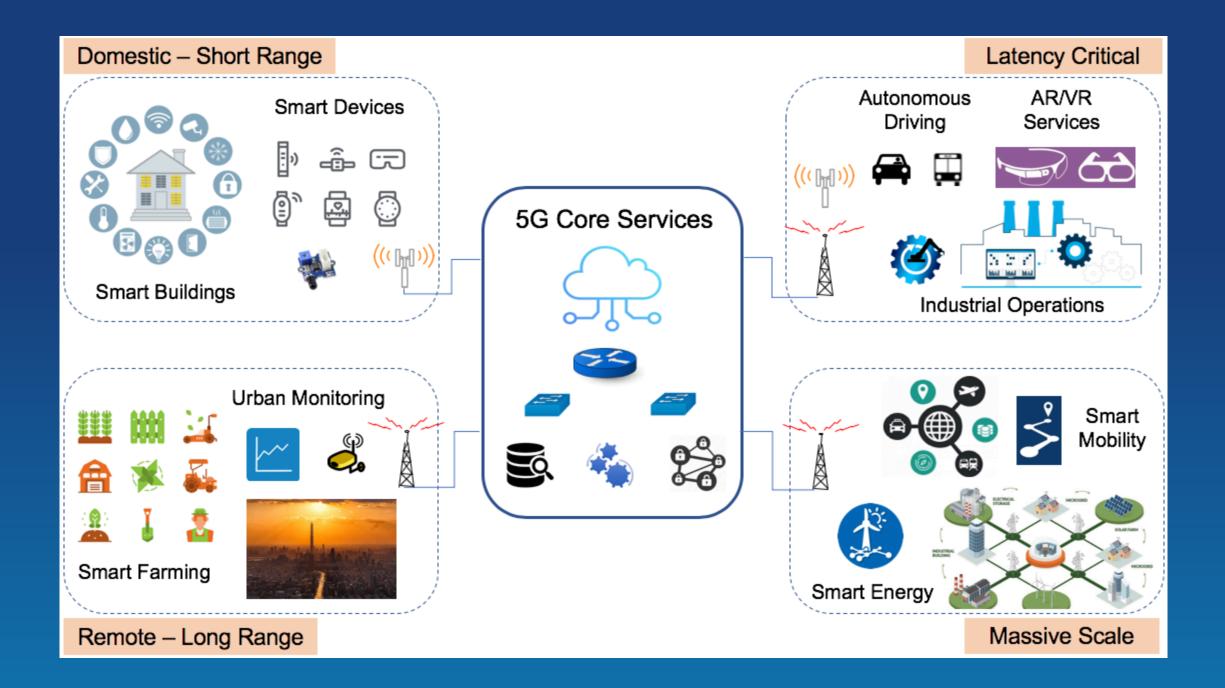
mmW Test Solutions for 5G-FR2 Daniel Bock, Ph.D.



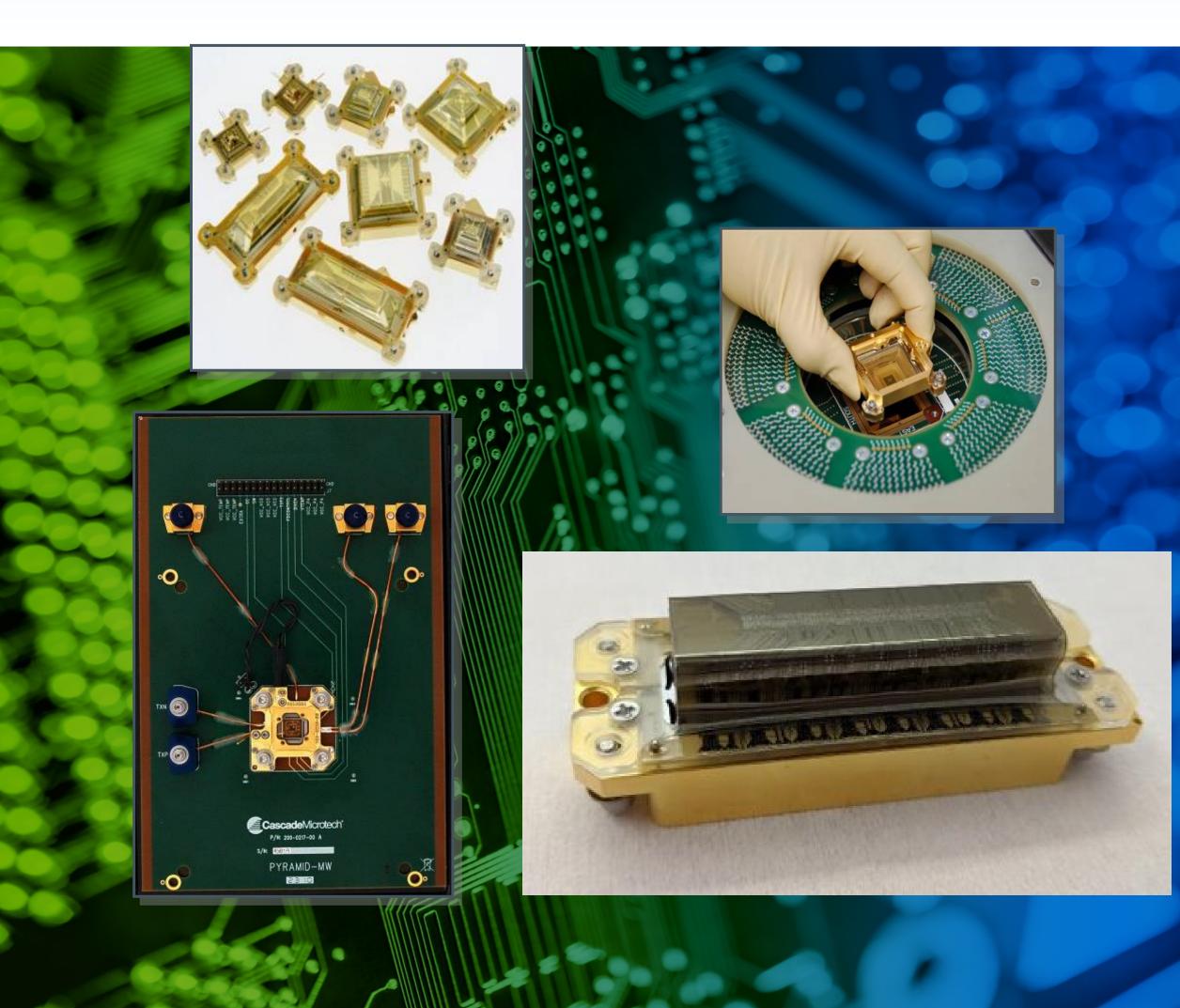
5G Creating New Markets for RF IC Chips

- 5G is increasing the markets for RF chips:
 - Short range Personal Smart Devices/Buildings
 - Long Range: Smart Farming/Urban Monitoring
 - Latency Critical: Autonomous Driving/AR and VR services/Industrial Monitoring
 - Massive Scale: Smart Energy/Smart Mobility





FFI Probe Cards for RF KGD Production



RF Probe Cards from Form Factor provide:

- Frequency range to 81+ GHz with better than -10 dB Return loss to maximize test accuracy out to specified frequency
- Custom layout to match your die to minimize number of touchdowns
- Short, low-loss lines to minimize resonances and overall loss in the measurement
- Low inductance supplies with bypass capacitors close to the DUT
- Low contact resistance
- Minimal pad damage to maintain yield

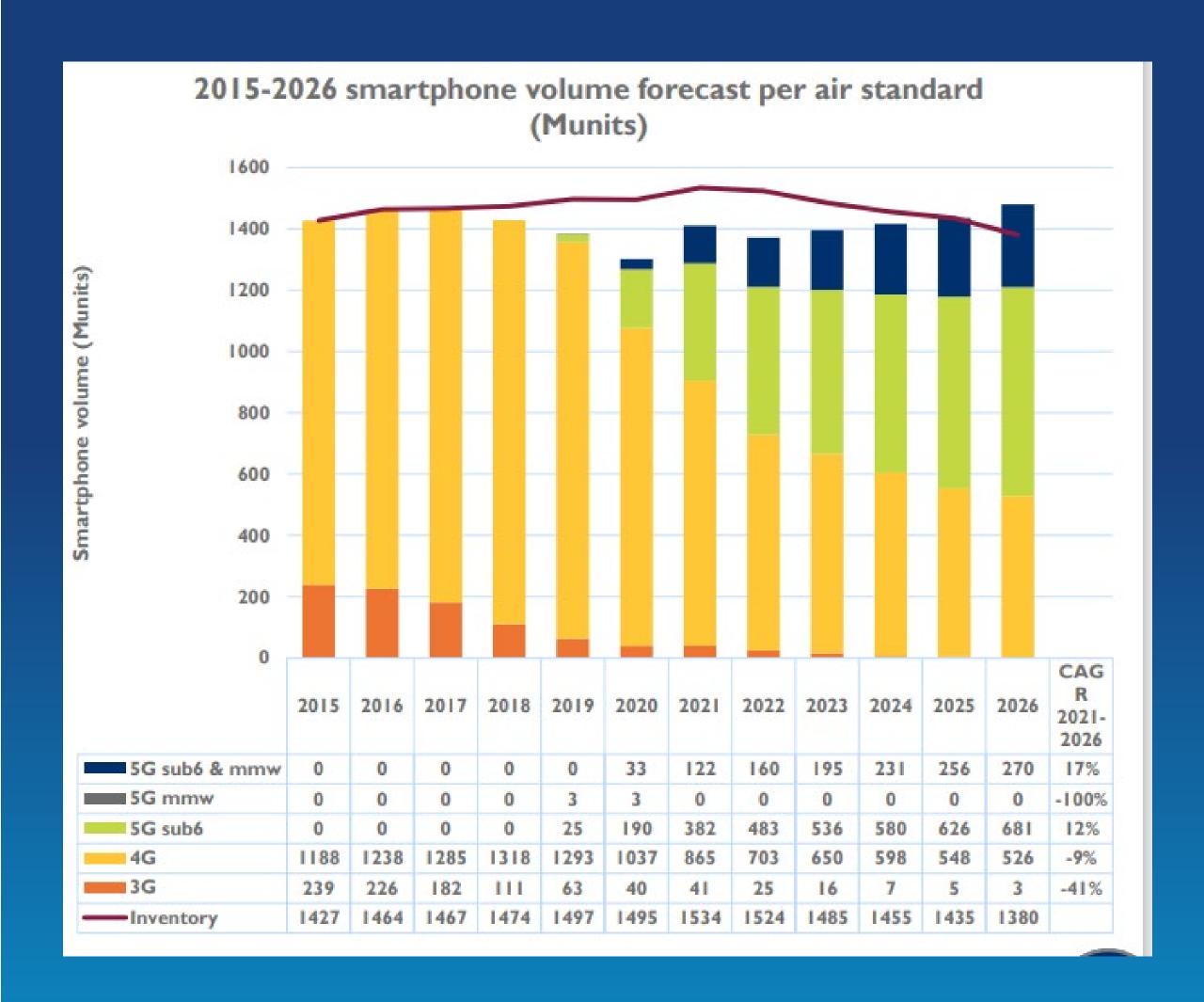




- Based on the Yole report on RF-FE from 2021, there will be more than a doubling in the number of smartphones operating at 5G FR2 (CAGR of 17%) from now to 2026
- Since each phone requires about 3 mmW modules, it is estimated that by 2026, more than 750M 5G mmW modules will need to be tested per year

Ref: Cellular RF Front-End Technologies for Mobile Handsets 2021. market and Technology Report 2021, Yole Development



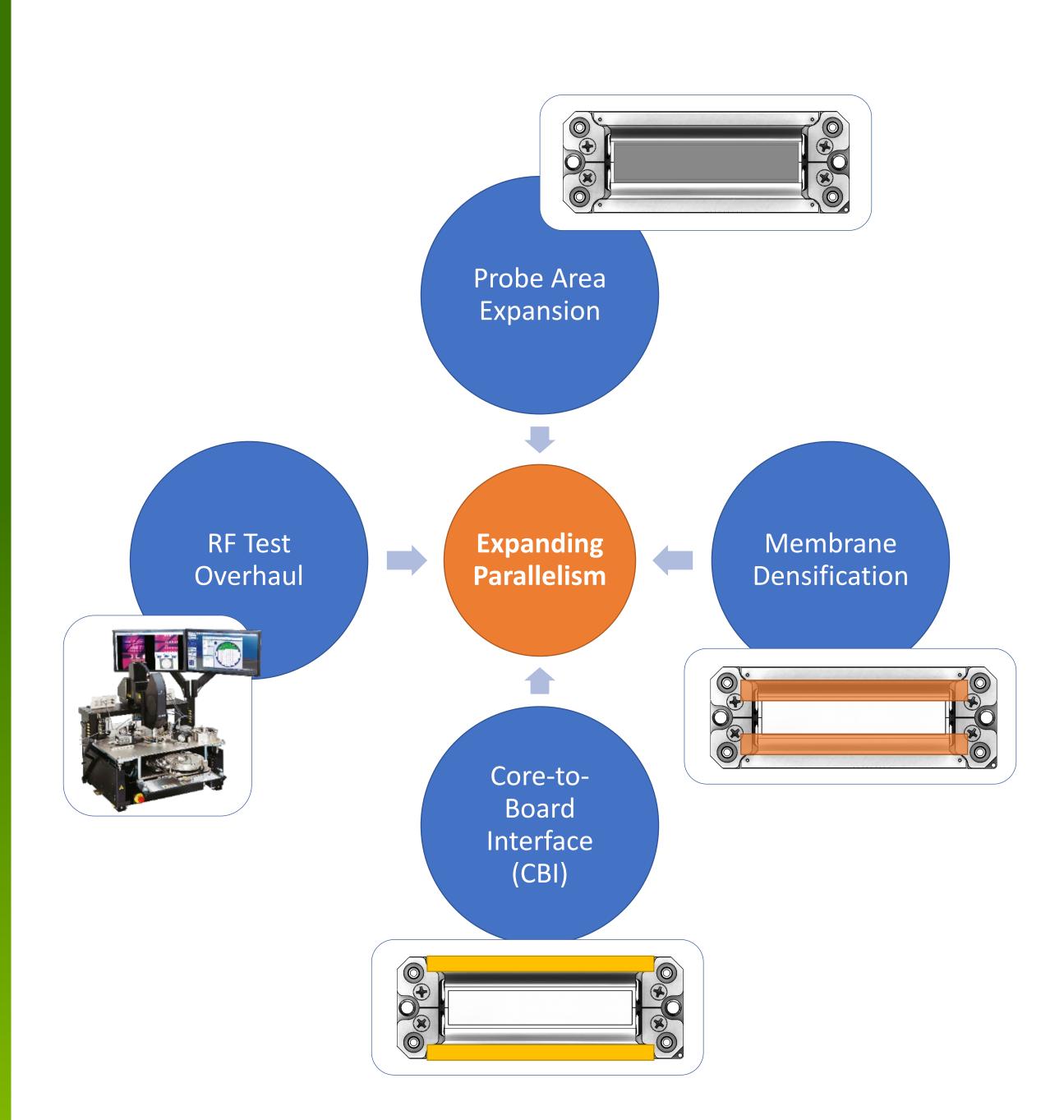


Expanding Test Parallelism

FormFactor's RF product evolution centralizes on increasing the active probing area and densifying the membrane while maintaining best-in-class RF measurements to address the increased mmW test parallelism



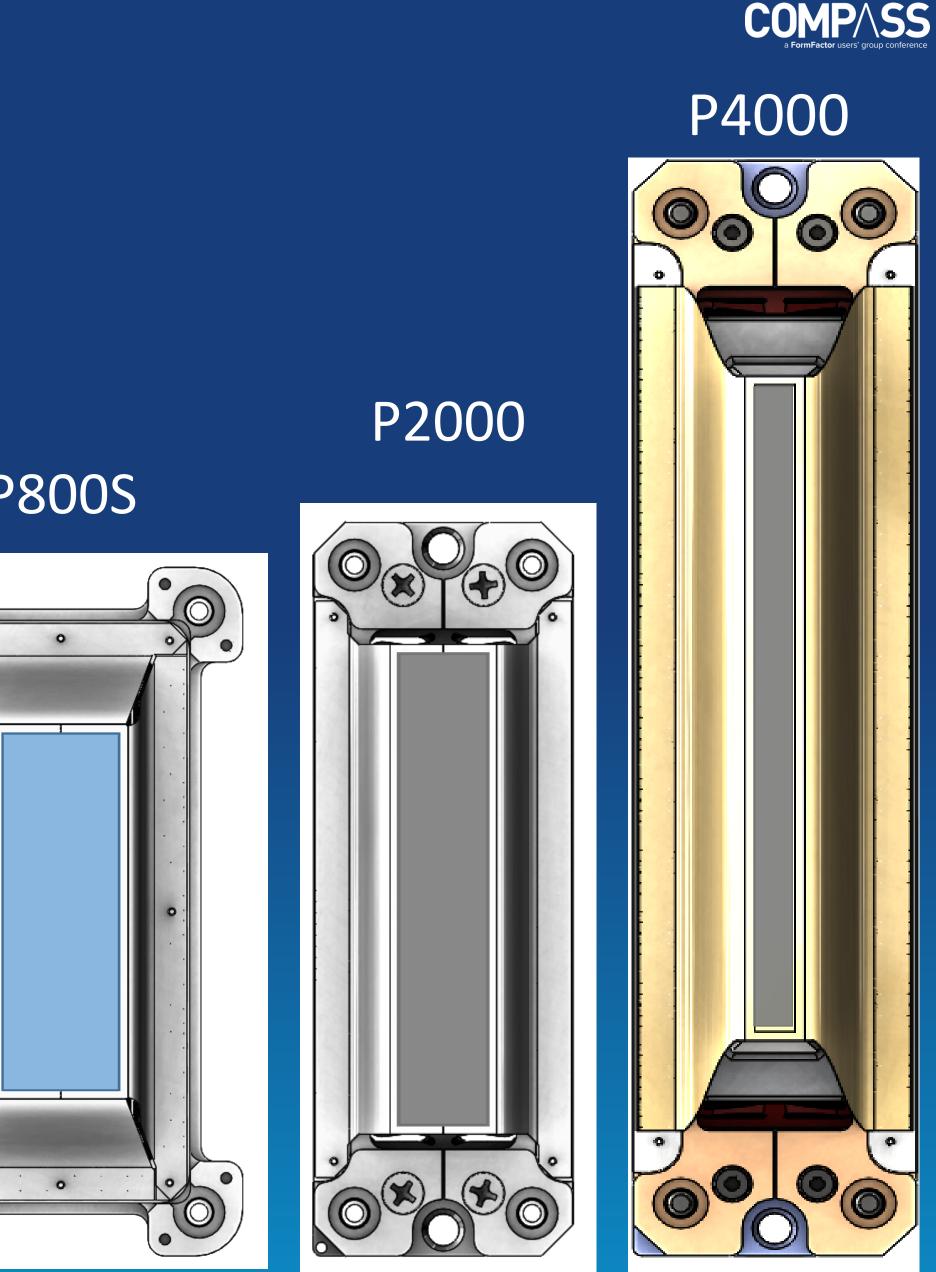
Pyramid P2000 x4 AiP Probe Core



Pyramid Probe Area Expansion

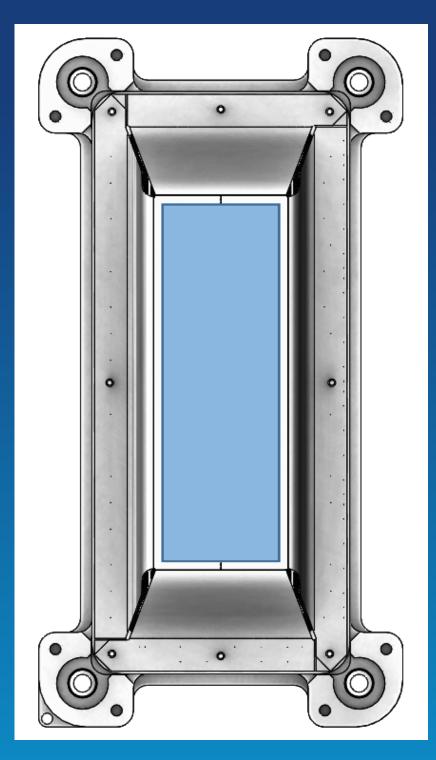
- New P2000 core design in Beta release to increase test capability
 - P2000 supports a 4x AiP layout
 - P2000 includes improved core-to-board interface density, increasing the number of I/O from 804 in P800S to 2112 on P2000
 - Will be in full release late 2021
- Pyramid membrane performance on all cores:
 - Excellent RF measurements
 - Stable CRES with consistent probe marks
 - Replaceable cores from tester
 - No off-stepping



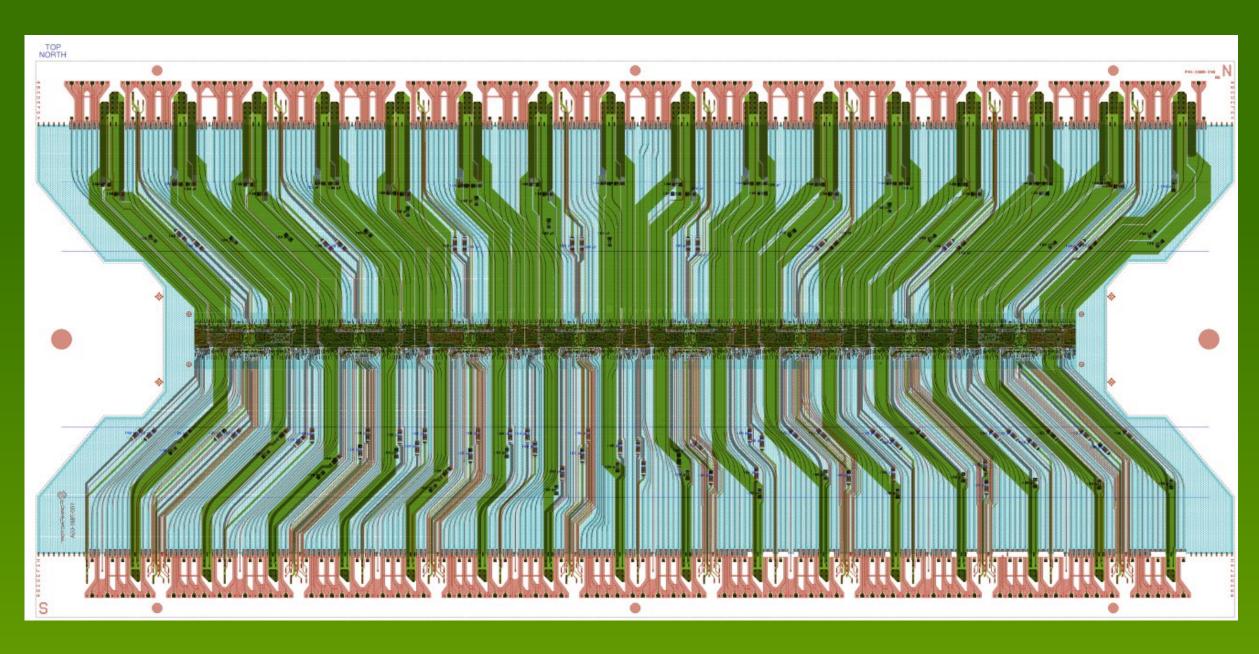


P2000

P800S



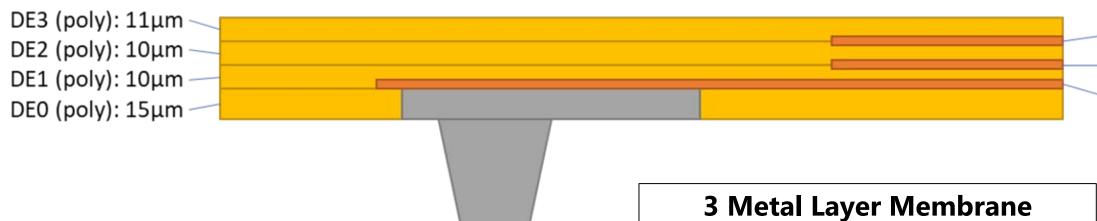
New Membrane Layer Count Capability



FFI has been working to improve our membrane fabrication capabilities

This includes improving:

Overall membrane yield improvements Increasing the number of layers in the membrane from 2 routing layers (2ML) to 3 routing layers (3ML) 3ML enables dense die breakout and routing



M3 (Au): 4μm M2 (Au): 4μm M1 (Au): 4μm

2ML Performance with 1 mm Connector

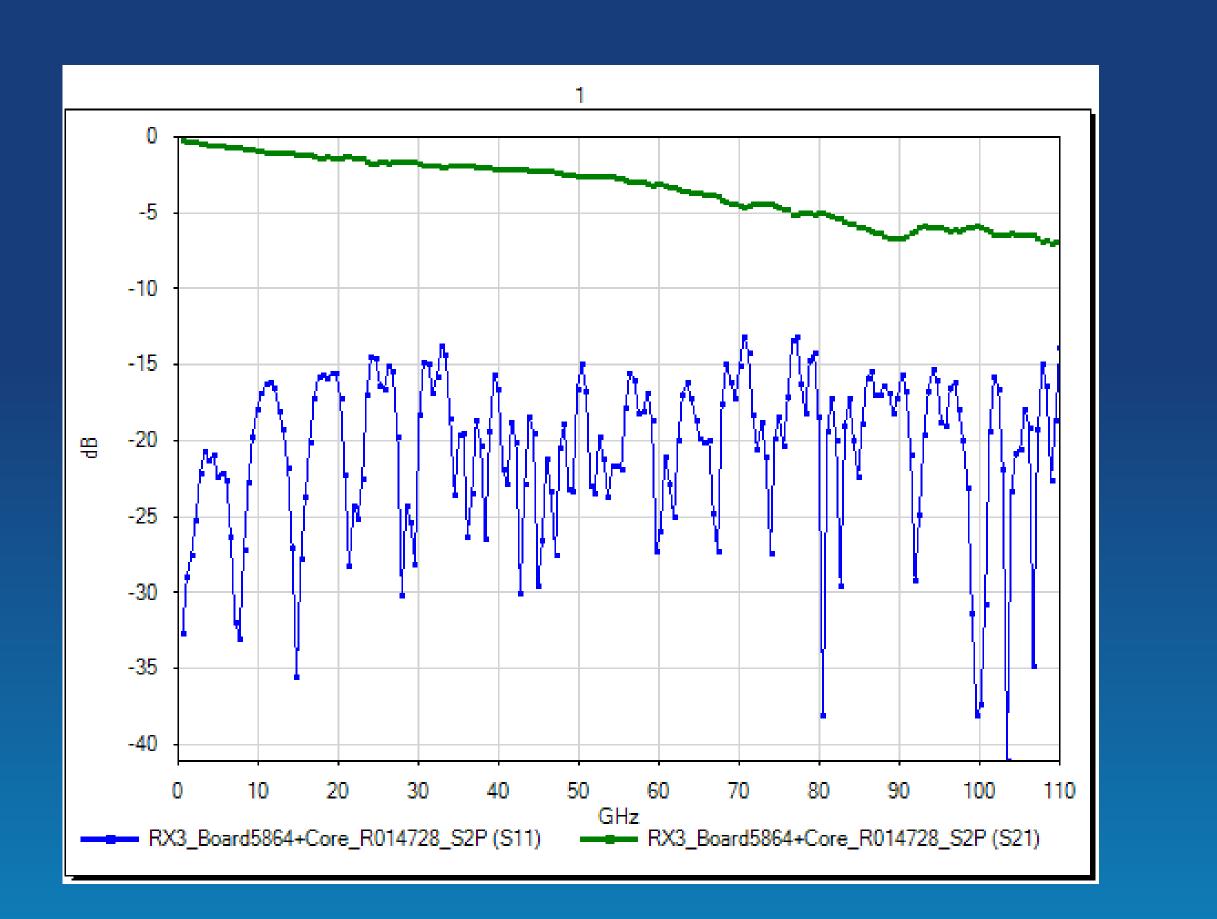
RFC-MW size core

Maximum probing area of 5.334 x 5.334 mm Test board used 1 mm RF connector (110 GHz) **Return loss (S11) spec Better than -10 dB at 81 GHz** Insertion loss (S21), typical

Better than -6 dB at 81 GHz

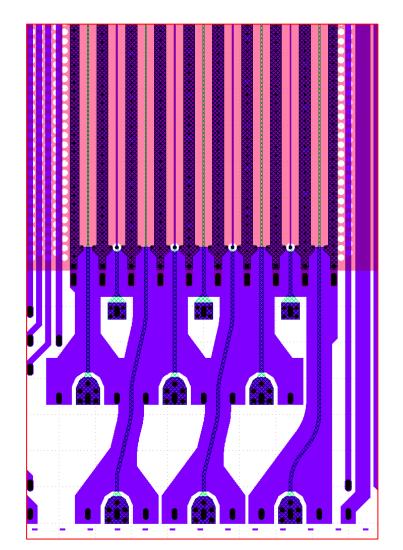
Actual performance dependent upon specific design of DUT



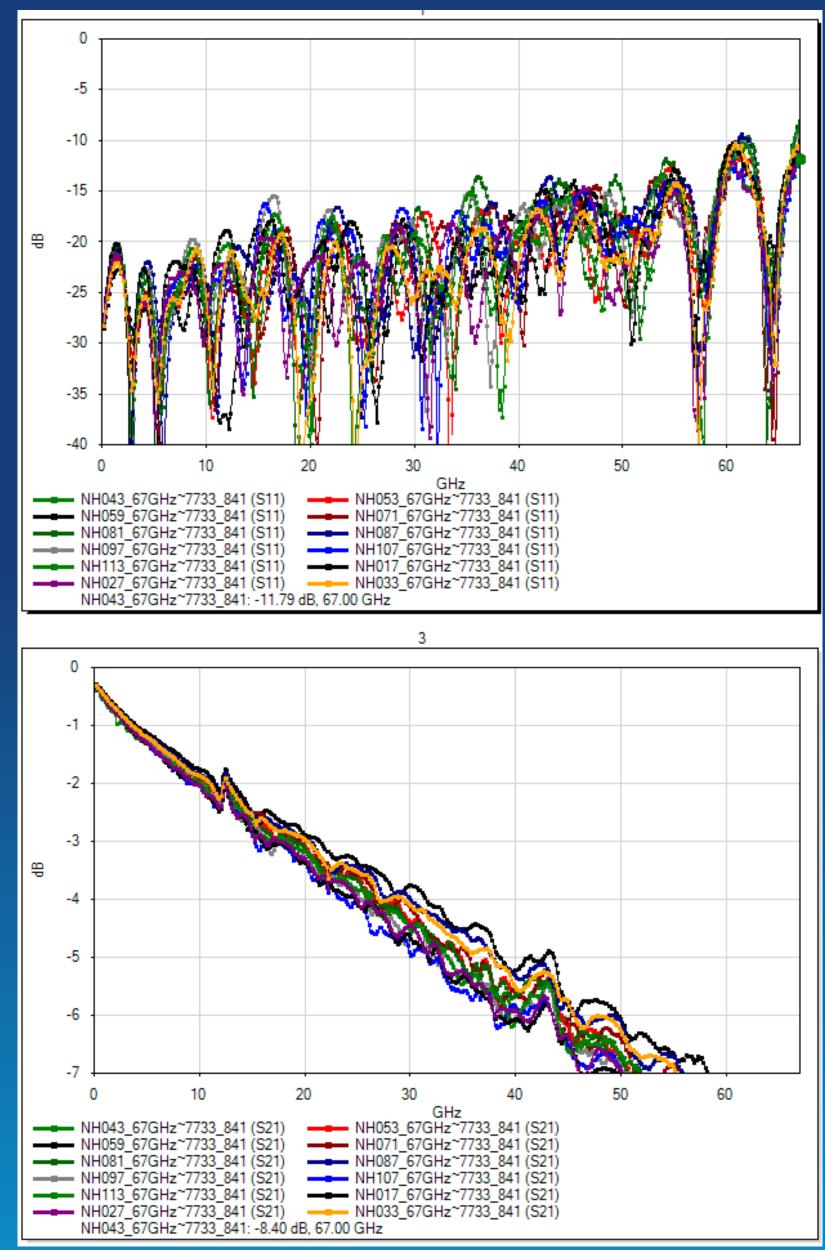


3ML on P2000 Performance

- P2000 sized core using 3ML transmission lines
 - The traces are longer than in other core designs, increasing loss
 - Maintains the better than -10 dB RL out to 55 GHz with good margin
 - This is the layout of the P2000, using microstrip for the core-to-board interface for isolating lines from PCB and for increasing density, but going to CPW on the wing for best performance



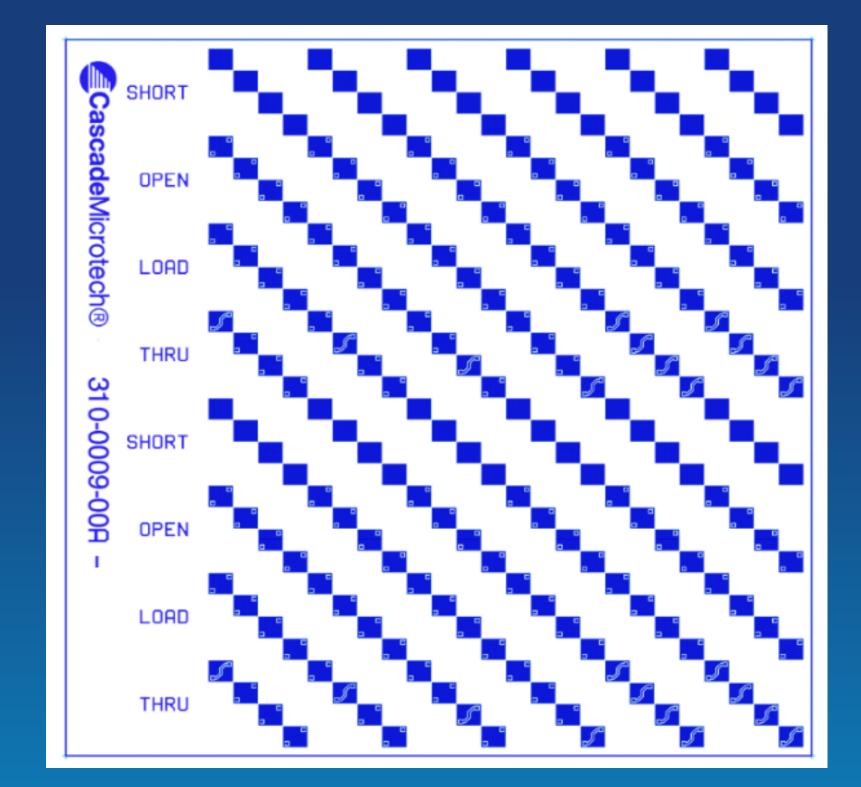




Cascade Custom Calibration Substrate

- Designed to exactly match the die layout
- Supports multi-DUT calibration
 - Ability to control the RF impedance of all lines simultaneously for more accurate calibration
 - Uncontrolled RF lines can resonate through excited currents and fields
- Standard 50 Ω loads as well as non-standard loads are available
- Accuracy guaranteed to 1%
- Designed and built by FormFactor. Ships in same box as the probehead





Summary of Benefits

- Ship KGD: Performance Test to Product Specifications
 - Controlled Impedance Signal Traces
 - High-Power Transmission
 - High-Bandwidth 81+ GHz RF signals
 - Excellent Signal Isolation
 - Accurate Package Emulation
- New Core size to increase the parallelism capability for 5G
- Full Calibration Solutions
- Probe all Pads and Solder Balls
 - Less damage and particle-generation
- Lower your Cost-of-Ownership
 - Multi-Site testing
 - Lower Maintenance Overheads







THANK YOU